Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/671,592	YAMADA ET AL.	
Examiner	Art Unit	_
Chris C. Chu	2815	

	SEARCHED			
Class	Subclass	Date	Examiner	
257	690, 691, 701, 584 and 678	8/16/2005	C.C.	
361	728 & 772	8/16/2005	C.C.	
174	52.1&52.4	8/16/2005	C.C.	
		:		
		<b>₹1</b> 11		

INT	INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner			
as same	as above	8/16/2005	c.c.			
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
·	DATE	EXMR		
Searched in USPAT; US-PGPUB; USOCR; EPO; JPO; DERWENT; and IBM_TDB;	8/16/2005	C.C.		
Consulted with David E. Graybill 257/584, 690, 691 & 701	2/24/2005	c.c.		
Consulted with S. Clark & Roy Potter No search area	2/28/2005	C.C.		
Consulted with Jerome Jackson	8/16/2005	c.c.		